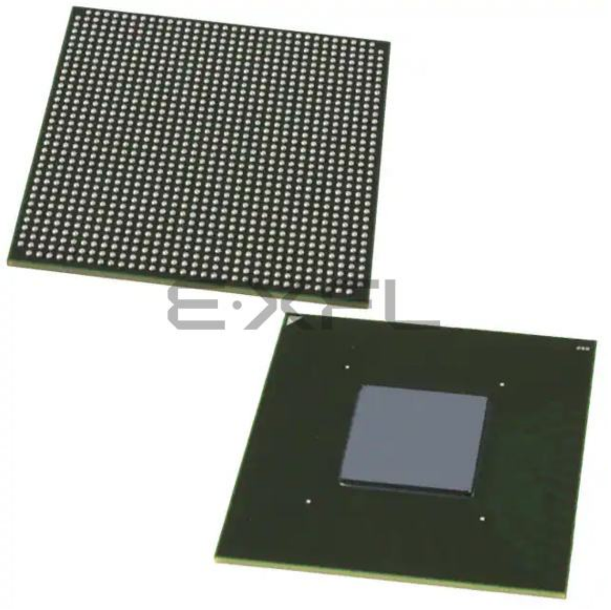

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	17110
Number of Logic Elements/Cells	362000
Total RAM Bits	19822592
Number of I/O	544
Number of Gates	-
Voltage - Supply	1.07V ~ 1.13V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1152-BBGA, FCBGA Exposed Pad
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agxmb3g4f35i5g

Symbol	Description	Maximum	Unit
$I_{XCVR\text{-}RX\ (DC)}$	DC current per transceiver receiver (RX) pin	50	mA

Internal Weak Pull-Up Resistor

All I/O pins, except configuration, test, and JTAG pins, have an option to enable weak pull-up.

Table 1-13: Internal Weak Pull-Up Resistor Values for Arria V Devices

Symbol	Description	Condition (V)[11]	Value[12]	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you have enabled the programmable pull-up resistor option.	V_{CCIO} = 3.3 ±5%	25	kΩ
		V_{CCIO} = 3.0 ±5%	25	kΩ
		V_{CCIO} = 2.5 ±5%	25	kΩ
		V_{CCIO} = 1.8 ±5%	25	kΩ
		V_{CCIO} = 1.5 ±5%	25	kΩ
		V_{CCIO} = 1.35 ±5%	25	kΩ
		V_{CCIO} = 1.25 ±5%	25	kΩ
		V_{CCIO} = 1.2 ±5%	25	kΩ

Related Information

Arria V GT, GX, ST, and SX Device Family Pin Connection Guidelines
Provides more information about the pins that support internal weak pull-up and internal weak pull-down features.

---

(10) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}|$ = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.

(11) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

(12) Valid with ±10% tolerances to cover changes over PVT.

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)(16)			$V_{ICM(DC)}$ (V)			V_{OD} (V)(17)			V_{OCM} (V)(17)(18)		
	Min	Typ	Max	Min	Condition	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
PCML	Transmitter, receiver, and input reference clock pins of high-speed transceivers use the PCML I/O standard. For transmitter, receiver, and reference clock I/O pin specifications, refer to Transceiver Specifications for Arria V GX and SX Devices and Transceiver Specifications for Arria V GT and ST Devices tables.														
2.5 V LVDS(19)	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	D_{MAX} ≤ 1.25 Gbps	1.80	0.247	—	0.6	1.125	1.25	1.375
						—	1.05	D_{MAX} > 1.25 Gbps	1.55						
RSDS (HIO)(20)	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.25	—	1.45	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS (HIO)(21)	2.375	2.5	2.625	200	—	600	0.300	—	1.425	0.25	—	0.6	1	1.2	1.4
LVPECL(22)	—	—	—	300	—	—	0.60	D_{MAX} ≤ 700 Mbps	1.80	—	—	—	—	—	—
							1.00	D_{MAX} > 700 Mbps	1.60						

Related Information

- **Transceiver Specifications for Arria V GX and SX Devices** on page 1-23
  Provides the specifications for transmitter, receiver, and reference clock I/O pin.

---

(16) The minimum V_{ID} value is applicable over the entire common mode range, V_{CM}.

(17) R_L range: $90 \le R_L \le 110\ \Omega$.

(18) This applies to default pre-emphasis setting only.

(19) For optimized LVDS receiver performance, the receiver voltage input range must be within 1.0 V to 1.6 V for data rates above 1.25 Gbps and 0 V to 1.85 V for data rates below 1.25 Gbps.

(20) For optimized RSDS receiver performance, the receiver voltage input range must be within 0.25 V to 1.45 V.

(21) For optimized Mini-LVDS receiver performance, the receiver voltage input range must be within 0.3 V to 1.425 V.

(22) For optimized LVPECL receiver performance, the receiver voltage input range must be within 0.85 V to 1.75 V for data rates above 700 Mbps and 0.45 V to 1.95 V for data rates below 700 Mbps.

Figure 1-9: SPI Master Timing Diagram

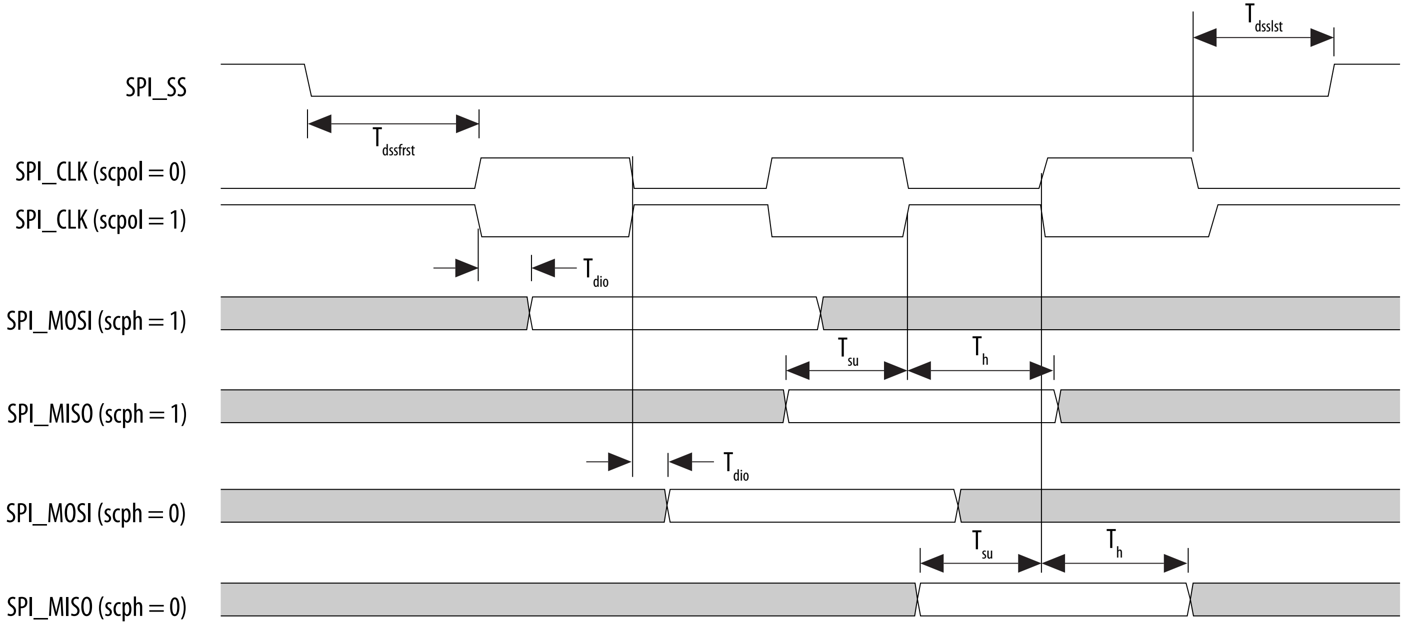


Table 1-53: SPI Slave Timing Requirements for Arria V Devices

The setup and hold times can be used for Texas Instruments SSP mode and National Semiconductor Microwire mode.

Symbol	Description	Min	Max	Unit
T_{clk}	CLK clock period	20	—	ns
T_s	MOSI Setup time	5	—	ns
T_h	MOSI Hold time	5	—	ns
T_{suss}	Setup time SPI_SS valid before first clock edge	8	—	ns
T_{hss}	Hold time SPI_SS valid after last clock edge	8	—	ns
T_d	MISO output delay	—	6	ns

Symbol	Description	Min	Max	Unit
T_{dh} (89)	Data to write enable hold time	5	—	ns
T_{cea}	Chip enable to data access time	—	25	ns
T_{rea}	Read enable to data access time	—	16	ns
T_{rhz}	Read enable to data high impedance	—	100	ns
T_{rr}	Ready to read enable low	20	—	ns

Figure 1-17: NAND Command Latch Timing Diagram

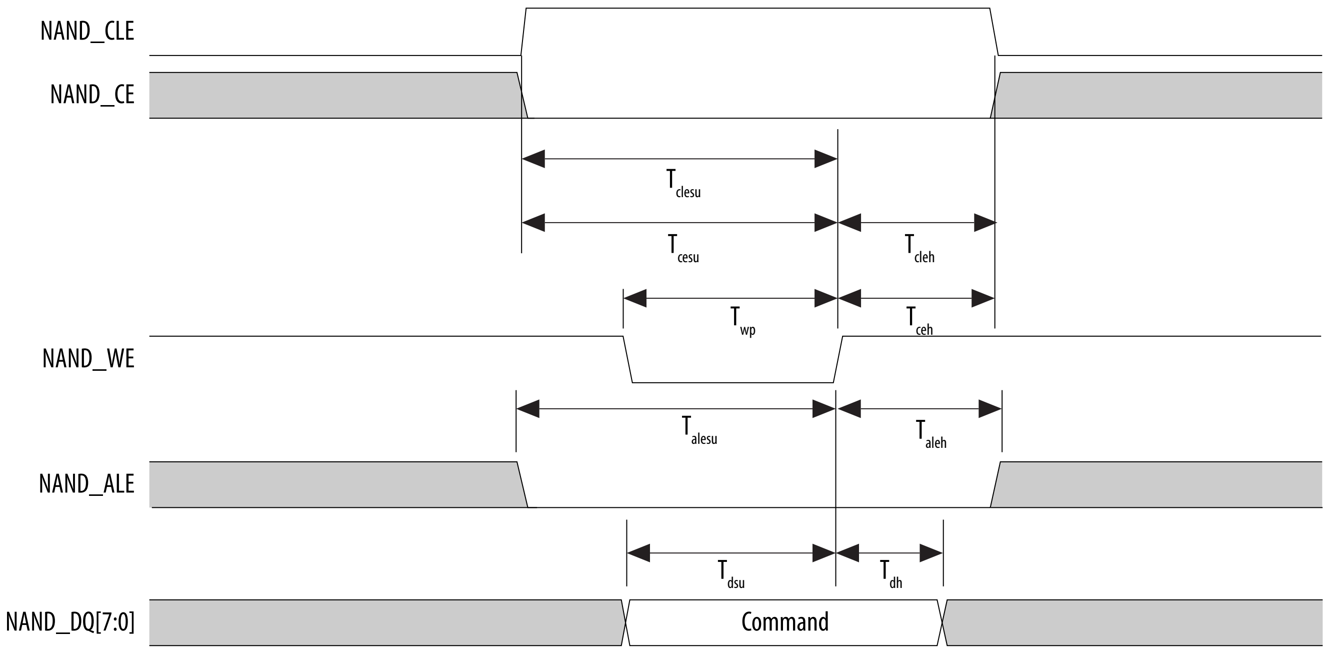
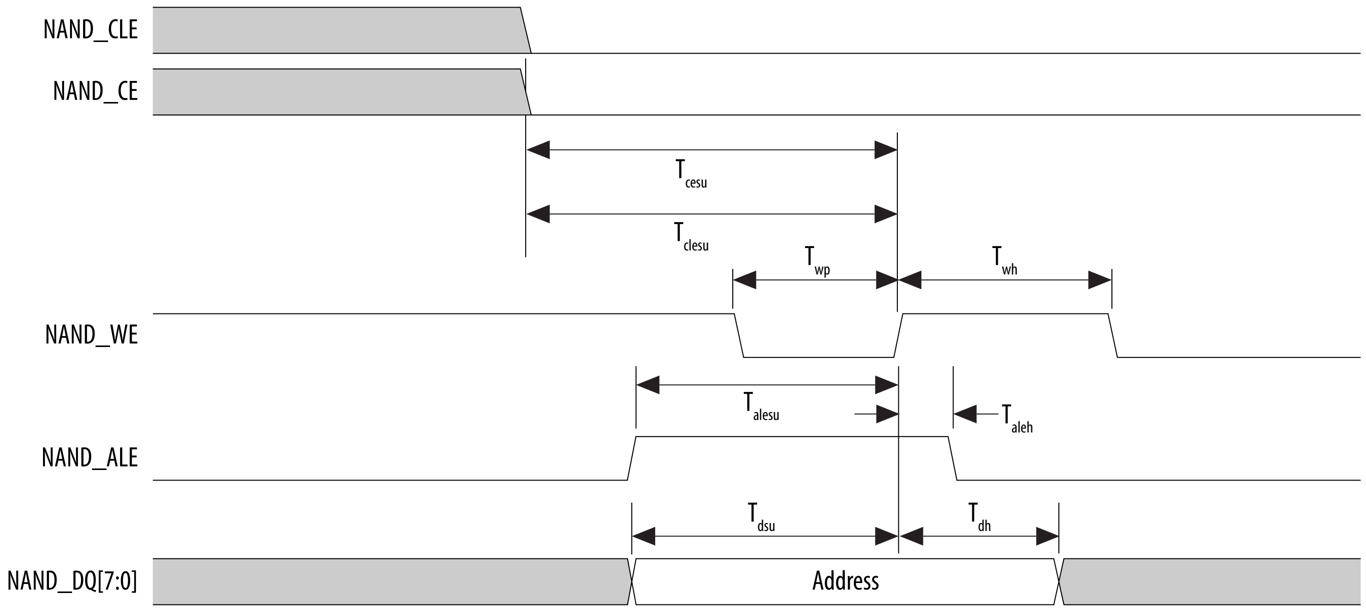


Figure 1-18: NAND Address Latch Timing Diagram



FPP Configuration Timing when DCLK-to-DATA[] >1

Table 1-67: FPP Timing Parameters When DCLK-to-DATA[] Ratio is >1 for Arria V Devices

Use these timing parameters when you use the decompression and design security features.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CF2CD}	`nCONFIG` low to `CONF_DONE` low	—	600	ns
t_{CF2ST0}	`nCONFIG` low to `nSTATUS` low	—	600	ns
t_{CFG}	`nCONFIG` low pulse width	2	—	µs
t_{STATUS}	`nSTATUS` low pulse width	268	1506(98)	µs
t_{CF2ST1}	`nCONFIG` high to `nSTATUS` high	—	1506(99)	µs
t_{CF2CK}(100)	`nCONFIG` high to first rising edge on `DCLK`	1506	—	µs
t_{ST2CK}(100)	`nSTATUS` high to first rising edge of `DCLK`	2	—	µs
t_{DSU}	`DATA[]` setup time before rising edge on `DCLK`	5.5	—	ns
t_{DH}	`DATA[]` hold time after rising edge on `DCLK`	$N - 1/f_{DCLK}$(101)	—	s
t_{CH}	`DCLK` high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	`DCLK` low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	`DCLK` period	$1/f_{MAX}$	—	s
f_{MAX}	`DCLK` frequency (FPP ×8/ ×16)	—	125	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	`CONF_DONE` high to user mode(102)	175	437	µs

---

(98) This value can be obtained if you do not delay configuration by extending the `nCONFIG` or `nSTATUS` low pulse width.

(99) This value can be obtained if you do not delay configuration by externally holding `nSTATUS` low.

(100) If `nSTATUS` is monitored, follow the t_{ST2CK} specification. If `nSTATUS` is not monitored, follow the t_{CF2CK} specification.

(101) N is the `DCLK`-to-`DATA[]` ratio and f_{DCLK} is the `DCLK` frequency of the system.

(102) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CF2CK}(105)	`nCONFIG` high to first rising edge on `DCLK`	1506	—	µs
t_{ST2CK}(105)	`nSTATUS` high to first rising edge of `DCLK`	2	—	µs
t_{DSU}	`DATA[]` setup time before rising edge on `DCLK`	5.5	—	ns
t_{DH}	`DATA[]` hold time after rising edge on `DCLK`	0	—	ns
t_{CH}	`DCLK` high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	`DCLK` low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	`DCLK` period	$1/f_{MAX}$	—	s
f_{MAX}	`DCLK` frequency	—	125	MHz
t_{CD2UM}	`CONF_DONE` high to user mode(106)	175	437	µs
t_{CD2CU}	`CONF_DONE` high to `CLKUSR` enabled	4 × maximum `DCLK` period	—	—
t_{CD2UMC}	`CONF_DONE` high to user mode with `CLKUSR` option on	t_{CD2CU} + (T_{init} × `CLKUSR` period)	—	—
T_{init}	Number of clock cycles required for device initialization	8,576	—	Cycles

Related Information

PS Configuration Timing

Provides the PS configuration timing waveform.

---

(105) If `nSTATUS` is monitored, follow the t_{ST2CK} specification. If `nSTATUS` is not monitored, follow the t_{CF2CK} specification.

(106) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

Variant	Member Code	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits)
Arria V GX	A1	71,015,712	439,960
	A3	71,015,712	439,960
	A5	101,740,800	446,360
	A7	101,740,800	446,360
	B1	137,785,088	457,368
	B3	137,785,088	457,368
	B5	185,915,808	463,128
	B7	185,915,808	463,128
Arria V GT	C3	71,015,712	439,960
	C7	101,740,800	446,360
	D3	137,785,088	457,368
	D7	185,915,808	463,128
Arria V SX	B3	185,903,680	450,968
	B5	185,903,680	450,968
Arria V ST	D3	185,903,680	450,968
	D5	185,903,680	450,968

Minimum Configuration Time Estimation

Table 1-73: Minimum Configuration Time Estimation for Arria V Devices

The estimated values are based on the configuration `.rbf` sizes in Uncompressed .rbf Sizes for Arria V Devices table.

Term	Definition
V_{OX}	Output differential cross point voltage
W	High-speed I/O block—Clock boost factor

Document Revision History

Date	Version	Changes

December 2016	2016.12.09	• Updated V_{ICM} (AC coupled) specifications in Receiver Specifications for Arria V GX and SX Devices table.
		• Added maximum specification for T_d in Management Data Input/Output (MDIO) Timing Requirements for Arria V Devices table.
		• Updated T_{init} specifications in the following tables:
		  • FPP Timing Parameters When DCLK-to-DATA[] Ratio is 1 for Arria V Devices
		  • FPP Timing Parameters When DCLK-to-DATA[] Ratio is >1 for Arria V Devices
		  • AS Timing Parameters for AS ×1 and ×4 Configurations in Arria V Devices
		  • PS Timing Parameters for Arria V Devices

June 2016	2016.06.10	• Changed pin capacitance to maximum values.
		• Updated SPI Master Timing Requirements for Arria V Devices table.
		  • Added T_{su} and T_h specifications.
		  • Removed T_{dinmax} specifications.
		• Updated SPI Master Timing Diagram.
		• Updated T_{clk} spec from maximum to minimum in I^2C Timing Requirements for Arria V Devices table.

Arria V GZ Device Datasheet

2

2017.02.10

AV-51002

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This document covers the electrical and switching characteristics for Arria V GZ devices. Electrical characteristics include operating conditions and power consumption. Switching characteristics include transceiver specifications, core, and periphery performance. This document also describes I/O timing, including programmable I/O element (IOE) delay and programmable output buffer delay.

Related Information

Arria V Device Overview

For information regarding the densities and packages of devices in the Arria V GZ family.

Electrical Characteristics

Operating Conditions

When you use Arria V GZ devices, they are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of Arria V GZ devices, you must consider the operating requirements described in this datasheet.

Arria V GZ devices are offered in commercial and industrial temperature grades.

Commercial devices are offered in –3 (fastest) and –4 core speed grades. Industrial devices are offered in –3L and –4 core speed grades. Arria V GZ devices are offered in –2 and –3 transceiver speed grades.

Table 2-1: Commercial and Industrial Speed Grade Offering for Arria V GZ Devices

C = Commercial temperature grade; I = Industrial temperature grade.

Symbol	Description	Condition	Minimum[114]	Typical	Maximum [114]	Unit
V_I	DC input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	–40	—	100	°C
t_{RAMP}	Power supply ramp time	Standard POR	200 µs	—	100 ms	—
		Fast POR	200 µs	—	4 ms	—

Recommended Transceiver Power Supply Operating Conditions

Table 2-6: Recommended Transceiver Power Supply Operating Conditions for Arria V GZ Devices

Symbol	Description	Minimum [118]	Typical	Maximum[118]	Unit
V_{CCA_GXBL} [119], [120]	Transceiver channel PLL power supply (left side)	2.85	3.0	3.15	V
		2.375	2.5	2.625	
V_{CCA_GXBR} [119], [120]	Transceiver channel PLL power supply (right side)	2.85	3.0	3.15	V
		2.375	2.5	2.625	
V_{CCHIP_L}	Transceiver hard IP power supply (left side)	0.82	0.85	0.88	V
V_{CCHSSI_L}	Transceiver PCS power supply (left side)	0.82	0.85	0.88	V
V_{CCHSSI_R}	Transceiver PCS power supply (right side)	0.82	0.85	0.88	V

---

[114] The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

[118] This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

[119] This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.

[120] When using ATX PLLs, the supply must be 3.0 V.

Related Information

- **PowerPlay Early Power Estimator User Guide**
  For more information about the EPE tool.
- **PowerPlay Power Analysis**
  For more information about PowerPlay power analysis.

Power Consumption

Altera offers two ways to estimate power consumption for a design—the Excel-based Early Power Estimator and the Quartus II PowerPlay Power Analyzer feature.

Note: You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.

Related Information

- **PowerPlay Early Power Estimator User Guide**
  For more information about the EPE tool.
- **PowerPlay Power Analysis**
  For more information about PowerPlay power analysis.

I/O Pin Leakage Current

Table 2-8: I/O Pin Leakage Current for Arria V GZ Devices

If $V_O = V_{CCIO}$ to $V_{CCIOMax}$, 100 µA of leakage current per I/O is expected.

Symbol	Description	Conditions	Min	Typ	Max	Unit
I_I	Input pin	V_I = 0 V to $V_{CCIOMAX}$	–30	—	30	µA
I_{OZ}	Tri-stated I/O pin	V_O = 0 V to $V_{CCIOMAX}$	–30	—	30	µA

Bus Hold Specifications

Table 2-9: Bus Hold Parameters for Arria V GZ Devices

Parameter	Symbol	Conditions	V_{CCIO}										Unit
			1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I_{SUSL}	$V_{IN} > V_{IL}$ (maximum)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	µA
High sustaining current	I_{SUSH}	$V_{IN} < V_{IH}$ (minimum)	–22.5	—	–25.0	—	–30.0	—	–50.0	—	–70.0	—	µA
Low overdrive current	I_{ODL}	$0V < V_{IN} < V_{CCIO}$	—	120	—	160	—	200	—	300	—	500	µA
High overdrive current	I_{ODH}	$0V < V_{IN} < V_{CCIO}$	—	–120	—	–160	—	–200	—	–300	—	–500	µA
Bus-hold trip point	V_{TRIP}	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block.

Table 2-10: OCT Calibration Accuracy Specifications for Arria V GZ Devices

OCT calibration accuracy is valid at the time of calibration only.

Symbol/Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Supported data rate range	VCO post-divider L = 2	8000	—	12500	8000	—	10312.5	Mbps
	L = 4	4000	—	6600	4000	—	6600	Mbps
	L = 8 [155]	2000	—	3300	2000	—	3300	Mbps
$t_{pll\_powerdown}$ [156]	—	1	—	—	1	—	—	µs
t_{pll_lock} [157]	—	—	—	10	—	—	10	µs

Related Information

- **Arria V Device Overview**
  For more information about device ordering codes.
- **Transceiver Clocking in Arria V Devices**
  For more information about clocking ATX PLLs.
- **Dynamic Reconfiguration in Arria V Devices**
  For more information about reconfiguring ATX PLLs.

Fractional PLL

Table 2-28: Fractional PLL Specifications for Arria V GZ Devices

Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Arria V Device Overview*.

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[155] This clock can be further divided by central or local clock dividers making it possible to use ATX PLL for data rates < 1 Gbps. For more information about ATX PLLs, refer to the Transceiver Clocking in Arria V Devices chapter and the Dynamic Reconfiguration in Arria V Devices chapter.

[156] $t_{pll\_powerdown}$ is the PLL powerdown minimum pulse width.

[157] t_{pll_lock} is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.

Description	Min	Typ	Max	Unit
Diode ideality factor	1.006	1.008	1.010	—

Periphery Performance

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface. General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.

Note: The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

High-Speed Clock Specifications

Table 2-39: High-Speed Clock Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

For LVDS applications, you must use the PLLs in integer PLL mode.

Arria V GZ devices support the following output standards using true LVDS output buffer types on all I/O banks.

- True RSDS output standard with data rates of up to 230 Mbps
- True mini-LVDS output standard with data rates of up to 340 Mbps

Symbol	Conditions	C3, I3L			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
f_{HSCLK_in} (input clock frequency) True Differential I/O Standards (179)	Clock boost factor W = 1 to 40 (180)	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 (180)	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 (180)	5	—	420	5	—	420	MHz
f_{HSCLK_OUT} (output clock frequency)	—	5	—	625 (181)	5	—	525 (181)	MHz

Transmitter High-Speed I/O Specifications

Table 2-40: Transmitter High-Speed I/O Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

---

(179) This only applies to DPA and soft-CDR modes.

(180) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.

(181) This is achieved by using the LVDS clock network.

Duty Cycle Distortion (DCD) Specifications

Table 2-52: Worst-Case DCD on Arria V GZ I/O Pins

The DCD numbers do not cover the core clock network.

Symbol	C3, I3L		C4, I4		Unit
	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	%

Configuration Specification

POR Specifications

Table 2-53: Fast and Standard POR Delay Specification for Arria V GZ Devices

Select the POR delay based on the MSEL setting as described in the “Configuration Schemes for Arria V Devices” table in the *Configuration, Design Security, and Remote System Upgrades in Arria V Devices* chapter.

POR Delay	Minimum (ms)	Maximum (ms)
Fast	4	12 (202)
Standard	100	300

Related Information

Configuration, Design Security, and Remote System Upgrades in Arria V Devices

---

(202) The maximum pulse width of the fast POR delay is 12 ms, providing enough time for the PCIe hard IP to initialize after the POR trip.

JTAG Configuration Specifications

Table 2-54: JTAG Timing Parameters and Values for Arria V GZ Devices

Symbol	Description	Min	Max	Unit
t_{JCP}	TCK clock period	30	—	ns
t_{JCP}	TCK clock period	167 (203)	—	ns
t_{JCH}	TCK clock high time	14	—	ns
t_{JCL}	TCK clock low time	14	—	ns
$t_{JPSU (TDI)}$	TDI JTAG port setup time	2	—	ns
$t_{JPSU (TMS)}$	TMS JTAG port setup time	3	—	ns
t_{JPH}	JTAG port hold time	5	—	ns
t_{JPCO}	JTAG port clock to output	—	11 (204)	ns
t_{JPZX}	JTAG port high impedance to valid output	—	14 (204)	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	14 (204)	ns

Fast Passive Parallel (FPP) Configuration Timing

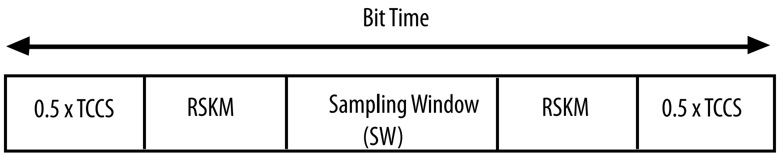
DCLK-to-DATA[] Ratio (r) for FPP Configuration

FPP configuration requires a different `DCLK-to-DATA[]` ratio when you turn on encryption or the compression feature.

---

(203) The minimum TCK clock period is 167 ns if VCCBAT is within the range 1.2V-1.5V when you perform the volatile key programming.

(204) A 1-ns adder is required for each V_{CCIO} voltage step down from 3.0 V. For example, t_{JPCO} = 12 ns if V_{CCIO} of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.

Term	Definition
R_L	Receiver differential input discrete resistor (external to the Arria V GZ device).
SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown: 
Single-ended voltage referenced I/O standard	The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: Single-Ended Voltage Referenced I/O Standard